Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/692,773	LEE, HEON	
Examiner	Art Unit	
 Eric B. Chen	1765	

	SEARCHED			
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (all databases) (UPDATED) - see search history printout	11/1/2005	EC
216/3,18,22,38,39,67,104,107,109 438/692,696,710,723-725,745,756, 757 (text search only) (UPDATED)	11/1/2005	EC
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